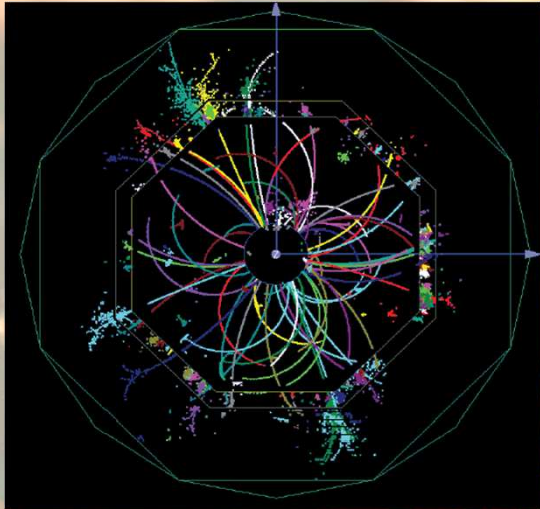


Plans for SKIROC and SPIROC



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Our plans for the ROCs chips



Engineering run in *AMS 0.35 μm SiGe* expected before the end of 2014

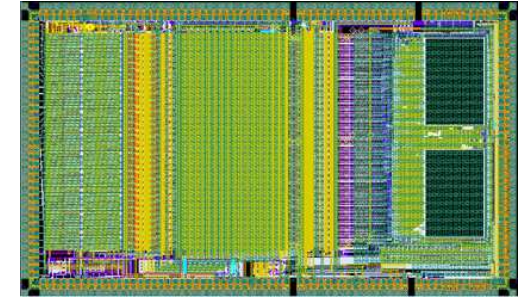
- Several chips will be produced. We will take the opportunity to submit a new version of **SKIROC 2b** and **SPIROC 2d**

These chips will be an intermediate step before switching to 3rd generation chips

3rd generation ROC chips:

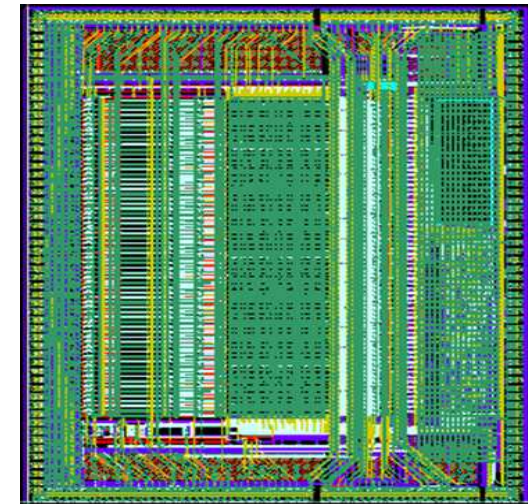
- The **64 (HR and SK) or 36 (SP) channels** will be **independent for zero suppress**, meaning that only the hit channels will be memorized in the SCA
- **I2C link** for the slow control parameters
-

HARDROC 3 was submitted in Feb 2013 (funded by Aida). (see Nathalie's talk). **Feedback tests** are necessary before submitting any other third generation chip.



SPIROC 2

Analog HCAL
(SiPM)
36 ch. 32mm²



SKIROC 2

E CAL
(SIW)
64 ch. 70mm²

SKIROC2 and **SPIROC2** are very similar chips except for the very front-end stages. The SCA and the digital part are the same...

Many laboratory measurements and testbeam have been done on SKIROC 2 and SPIROC 2.

The feedback of the different users (HBU, EBU, and FEV) is crucial for us.

Towards the next SPIROC

Topics to keep in mind ...

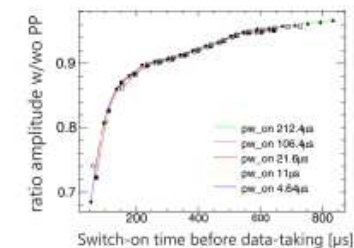
- > Pedestal shift @ huge signals, pedestal different for internal/external trigger.
- > Memory cell dependent amplitude decay. Solved by compensation caps.
- > Slow-Control configuration is problematic for long slabs.
- > Feedback of channel-wise trigger thresholds on the global threshold.
- > Random zero events and zero-results for the first trigger.
- > Poor uniformity of the input DACs.
- > Holdscan is different for HG/LG.
- > Trigger threshold width increases with threshold height.
- > Amplitude-to-threshold relation depends on preamp. setting and pulse shape.
- > TDC: Amplitude dependent time-shifts and channel-to-channel spread.
- > TDC: Result depends on which ramp is used and the memory cell.
- > TDC: big chip-to-chip spread of ramp slopes.

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Power and Power Pulsing (PP)

- > Aim: Switch on as short as possible before data taking starts (initial idea: 20 μ s).
- > Results with charge injection show a decreased amplitude response with PP.
- > Single-Pixel Spectra measurements show a reduced amplitude with PP.
- > Aimed power dissipation of 20 μ W per channel not reached yet.

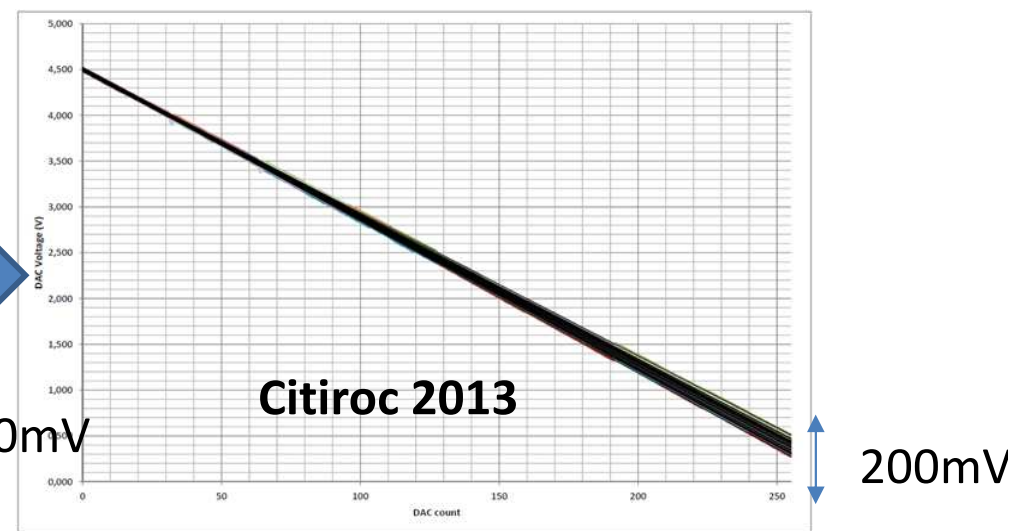
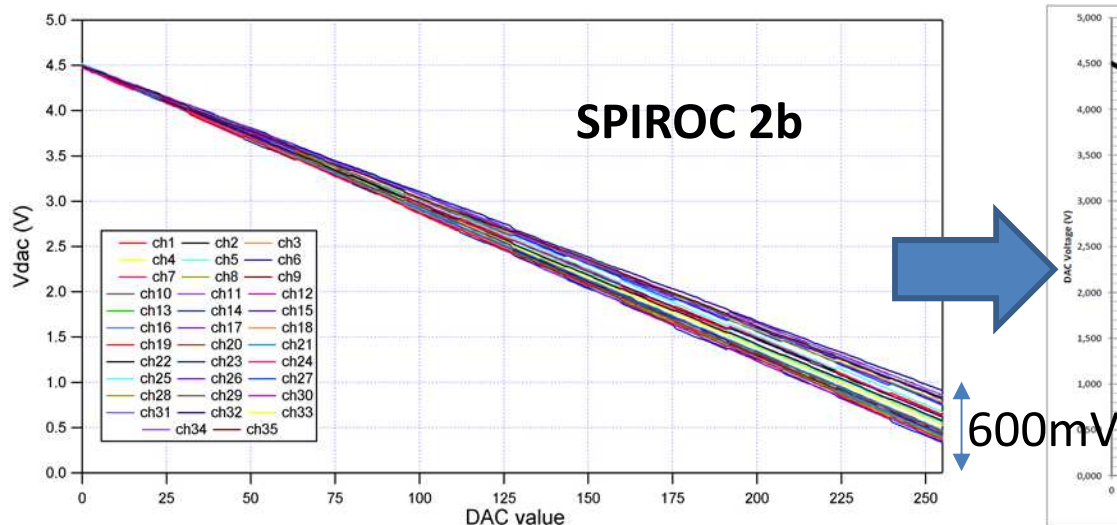
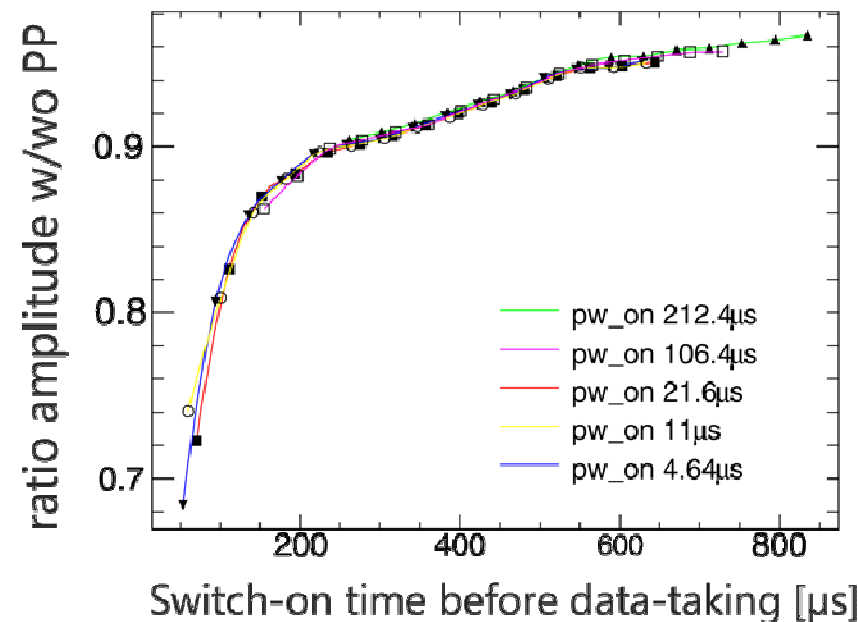


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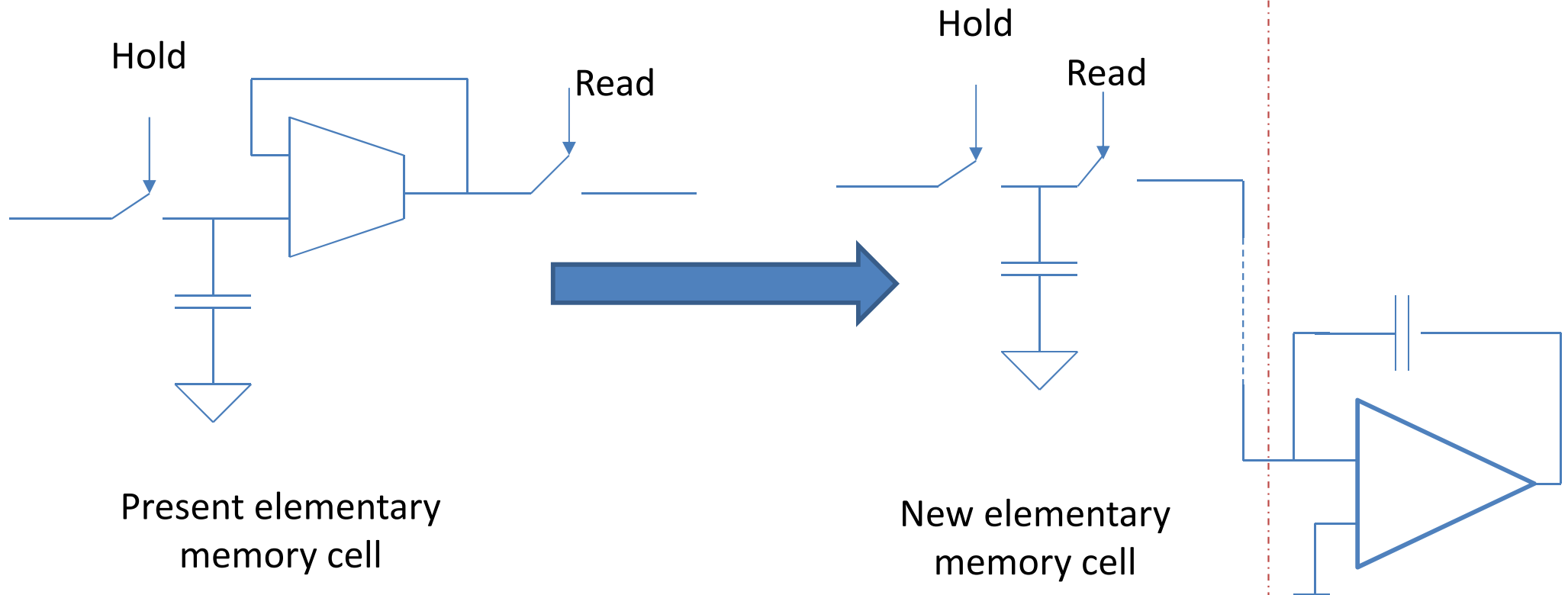


- Many issues already understood and solved in **SPIROC 2c**
will be in SPIROC 2d/SKIROC 2b
 - Pedestal shift @ huge signals, pedestal different for internal/external trigger.
 - Due to long distance cross-talk
 - Memory cell dependent amplitude decay (“rate effect”).
 - Due to switches on compensation capacitances
 - Influence of channel-wise trigger thresholds on the global threshold.
 - Due to internal parasitic resistances
 - Random zero events and zero-results for the first trigger.
 - Due to ADC management signals sequence
 - Holdscan is different for HG and LG
 - Due to cross-talk between HG and LG

- Power pulsing issue: far from the expected 20 μ s
 - A system must be implemented to help the preamp to recover in less than 20 μ s the ability to take data
- Input DACs uniformity:
 - performance noticeably improved but not yet satisfying (difficult due to the small power budget)

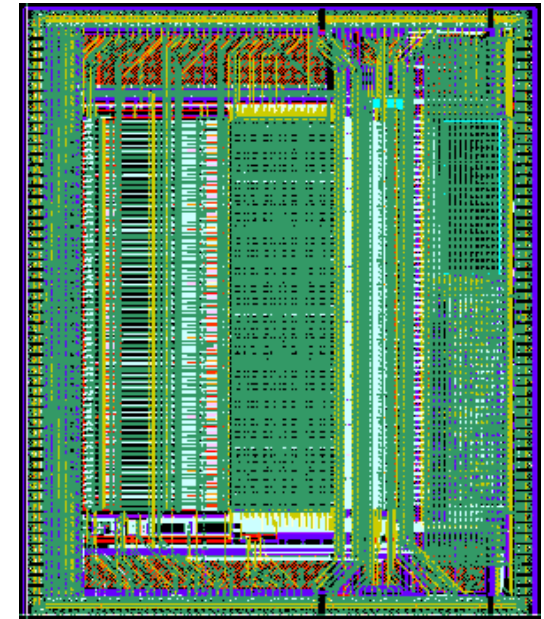


- The present analog memory system introduces an offset on each elementary cell : could be improved but droop to be checked



- Preamp choice : need to decrease sensitivity to vdda
 - At system level, on HBU, EBU and FEV
 - Preamp input stage
 - On chip power filtering
- Substrate coupling issue
- Power sequencing issue (« power up problem »)
- Reliability improvement (in particular the input DAC)
- TDC to be redone (as in petiroc)

- Exploration of a new technology for future
- Advantages of the XFAB 0.18 μm SOI HV technology :
 - SOI -> less coupling via substrate
 - Sustainable because used by the car industry
 - Masks cost lower thanks to multi-mask process
 - Dimensions theoretically reduced by a factor of 4 compared 0.35 μm . In practice : factor 2-3 expected)
- Drawbacks: we've never used this technology
 - **Building blocks** are necessary to be submitted before to check the technology. A PhD. student of LLR has started to work on it with our group.



SKIROC2 : 70 mm²
=> 70 k€ AMS
0.35 μm SiGe MPW
run (proto)



- Many laboratory measurements and testbeam have been done on SKIROC 2 and SPIROC 2. These measurements allow to understand all the chip features.
- The feedback from the different users (HBU, EBU, and FEV) is crucial for us.
- Submission of a **SKIROC 2b** and a **SPIROC 2d** during our engineering run (expected before the end of 2014) => intermediate step before switching to 3rd generation chip.
- In parallel, plans to submit building blocks in XFAB 0.18 μm SOI HV technology for second source.
- HARDROC 3 test feedback necessary before submitting SPIROC 3/SKIROC 3